

Notice of References Cited

Application/Control No.

10/046,710

Applicant(s)/Patent Under
Reexamination
KUWAYAMA ET AL.

Examiner

Chau N Nguyen

Art Unit

2831

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0050385	05-2002	Murakami et al.	174/74.00R
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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